

“Fast pixelated detectors in scanning transmission electron microscopy. part II : post acquisition data processing, visualization, and structural characterization”. Paterson GW, Webster RWH, Ross A, Paton KA, Macgregor TA, McGrouther D, MacLaren I, Nord M, *Microscopy And Microanalysis* **26**, 944 (2020). <http://doi.org/10.1017/S1431927620024307>